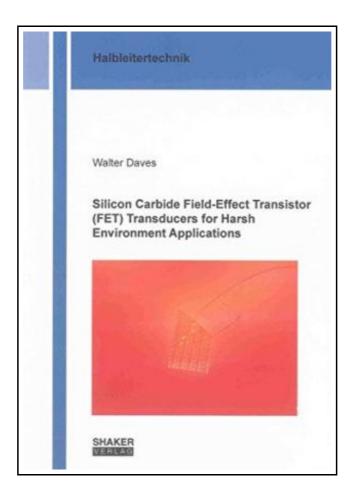
## Silicon Carbide Field-Effect Transistor (FET) Transducers for Harsh Environment Applications



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